

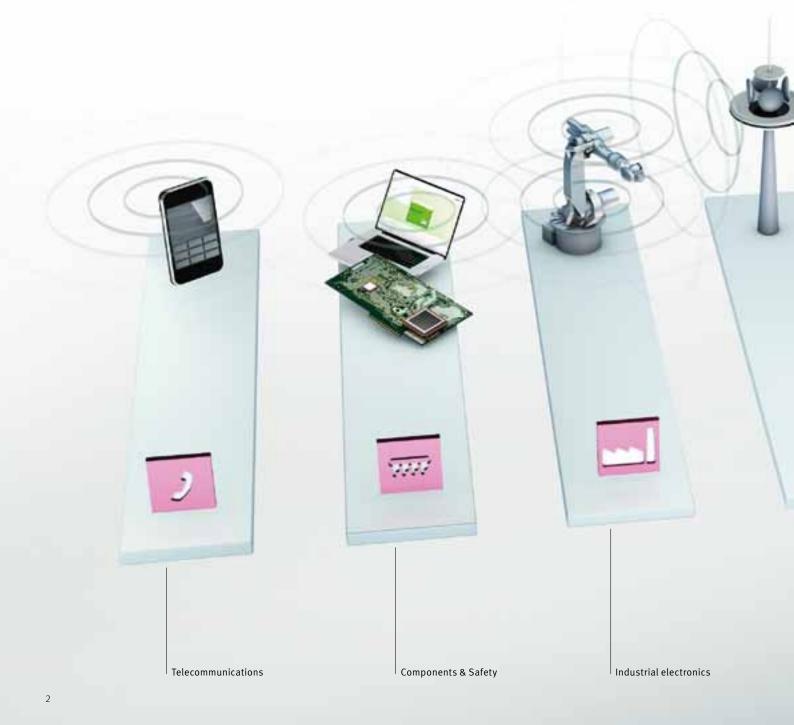


MULTIFUNCTION GENERATORS N5 + N7

N-SERIES



IGNORE EMC EARLY PAY THE PRICE LATER: OVERVIEW.



Many natural phenomena and those caused by electronic equipment result in serious EMC problems, if EMC is not considered from the very beginning.

Residential electronics

Renewable energy

THE WHOLE WORLD HAS STANDARDS. WE HAVE A SYSTEM.



The standards — are you familiar with all of them? Whether basic standard, generic standard, or product family standard — stipulated by law or demanded from the manufacturer: EM TEST has integrated all of them. Take advantage of the EM TEST test system.

It knows what's what and focuses specifically on your requirements.

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BURST	
	IEC/EN 61000-4-4 – Fast transients, bursts
	Switching operations of inductive loads result in interferences in supply networks. The fast, low-energy interference pulses are simulated with the generator and superimposed to the supply voltage and/or signal/data lines of the EUT.
SURGE	
	IEC/EN 61000-4-5 – Surge voltages
	Atmospheric discharges may damage electronic devices. A qualified test must be performed to check resistance to such high-energy interferences.
POWER FAILURE	
	IEC/EN 61000-4-11 – Voltage dips/short interruptions/voltage variations
	"Dips" is a term used to describe brownouts and voltage drops occurring in the supply network due to short-circuits or by sudden large changes of connected loads.
RINGWAVE	
4 1 0	IEC/EN 61000-4-12 – Interference resistance to damped oscillatory waves
	Switching operations in inductive circuits, short-circuits, or lightning strikes can cause oscillatory transients, also called ringwaves, in building installations. This affects power as well as signal/data and control lines. To check the immunity of such lines, the optional ringwave module is used.
DAMPED OSCILLATORY MAGNETIC	FIELD
	IEC/EN 61000-4-10 – Interference resistance to damped oscillatory magnetic fields
	This international standard refers to requirements for immunity to damped oscillatory magnetic fields as occur in low-voltage and high-voltage power supply systems.
TELECOM-SURGE	
	IEC/EN 61000-4-5, CCITT, FTZ 12TR1
	Telecommunication networks are exposed to lightning strikes and their associated effects. All telecommunication systems linked with lines installed outdoors therefore require reliable protection which needs to be tested.
MAGNETIC FIELDS	
Magnetfeld 50/60 Hz Magnetic	IEC/EN 61000-4-8 – Magnetic fields with a frequency of 50/60 Hz, IEC/EN 61000-4-9 – Pulsed magnetic fields
U Magnetic tield	Electronic devices and installations in residential and industrial areas can be affected by magnetic fields with low frequencies. Lightning strikes to buildings, antenna masts, and transient impacts due to faults in low-voltage, medium-voltage, and high- voltage systems can cause pulsed magnetic fields. These phenomena can be simulated with the generator and the magnetic field coil (optional), thereby providing interference resistance proof.

emiest

A THOUSAND WISHES, ONE SOLUTION ...

> Logical:	Easy, intuitive operation
> Relaxed:	Possible to set all parameters even
	during the test
> Direct:	Select from standard test levels
> Exact:	Statistical test options (random
	distribution)
> Viable:	Long-term viability regardless of
	standards
> More	Standard parameters must be exceeded
powerful:	(high performance reserves)
> Inclusive I:	Integrated interfaces (IEEE, USB)
> Inclusive II:	Integrated measuring technology
	(measured I/U values in display and
	CRO connection)
> Low cost:	Very good price/performance ratio
> Exemplary:	EM TEST service with accredited
	calibration labs

MODULAR ALL-IN-ONE ALL-ROUND TALENT! THE UCS 500N SERIES.





We present the compact and most powerful EM TEST test system of all times. Be ready for the future. For the best future of all times.

COMPACT POWER. THE N5.

01 MODULAR DESIGN

Up to 5 modules in one unit:

SURGE MODULE WITH 5,000 V, 1.2 μs/50 μs | 8 μs/20 μs

BURST/EFT MODULE WITH 5,500 V, 5 ns/50 ns | 1 MHz

POWER FAIL MODULE WITH 300 \

MAGNETIC FIELD, 1,000 A/m | 2,200 A/n

+ OPTIONAL TSURGE MODULE 5,000 V, 10 μs/700 μs

02 em.flow OPERATING CONCEPT

> Extremely easy to operate

- > Possible to set all parameters even during the test
- > Select directly from standard test levels
- > Statistical test options
- > Predefined tests

03 HIGH-RESOLUTION DISPLAY

- > Integrated measuring technology
- > Integrated I/U measurement

OUR INNOVATIONS:

- > Displays I/U values
- > Displays surge voltages and current during surge test
- Magnetic field test:
 Easy configuration and automatic
 parameter calculation



TURE PROOF

08

MAGNETIC FIELD

,000 V

S00N5

03

wemtest

BY UPGRADIN

04 CURRENT LIMITER em.safe > EUT protection during surge test

05 FULL SET OF INTERFACES

> USB, IEEE 488, CN, analog input/outputs

06 EASY TO CONNECT

> External motor variac

07

FAIL

30

01

- > Magnetic field coil, IEC/EN 61000-4-8/-9
- > Three-phase coupling/decoupling networks
 (burst/surge)
- > Coupling filter for I/O lines



07 PRICE Never before was so much so affordable!

08 VIABLE IN THE FUTURE

The device can be retrofitted and the software upgraded. When EM TEST performs the calibrations, an extended warranty is provided.

PURE POWER. THE N7.

TURE PROOF

08

EN DE

03

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w emtest

JCS SDON7

URGRAD

6,000

05

01 MODULAR DESIGN

Up to 6 modules in one unit:

- SURGE MODULE WITH 7,000 V, 1.2 μs/50 μs | 8 μs/20 μs
- BURST/EFT MODULE WITH 5,500 V, 5 ns/50 ns | 1 MHz
- POWER FAIL MODULE WITH 300 V
- MAGNETIC FIELD, 1,000 A/m | 3,000 A/m
- + OPTIONAL RINGWAVE MODULE 6,000 V, 100 kHZ
- + OPTIONAL TSURGE MODULE 7,000 V, 10 μs/700 μs

02 em.flow OPERATING CONCEPT

- > Extremely easy to operate
- > Possible to set all parameters even during the test
- > Select directly from standard test levels
- > Statistical test options
- > Predefined tests

03 HIGH-RESOLUTION DISPLAY

- Integrated measuring technology
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04 CURRENT LIMITER em.safe

05 FULL SET OF INTERFACES

> USB, IEEE 488, CN, analog input/outputs

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> External motor variac

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- > Three-phase coupling/decoupling networks
 (burst/surge)
- > Coupling filter for I/O lines



07 PRICE Never before was so much so affordable!

08 VIABLE IN THE FUTURE

The device can be retrofitted and the software upgraded. When EM TEST performs the calibrations, an extended warranty is provided.

BORN TO TEST: em.flow





Experience the em.flow: More efficient testing. Use standard and guideline libraries to quickly compile and start test sequences. Becoming one with the device — because it is easy. And easy is brilliant. Still have some wishes?

SIMPLY GET GOING! WITH em.flow

Comfortable one glance info: The multifunction display makes you a test champion. Easy navigation, right to the target! This is how working is fun.

YOUR CHOICE	
Burst IEC 61000-4-4 F1 : Ouickstart F2 : Standard test routines F3 : User test routines F1 F2 F3 F4 F5 F6 F7	NOTHING BUT CLARITY For example, if you decided to carry out a burst test, use the function keys next to select either Quickstart, standard test routines, or user test routines.
QUICKSTART: NOTHING IS FASTER!	
Burst 55880 [= 108 kHz U = 8.75 ms [r = 308 kHz Cpl = //r = endl. */- = + STOP Test time F1 F2 F3 F4 F5 F6 F7	THE MOST IMPORTANT SETTINGS ARE ALREADY PREDEFINED > All generator parameters at a single glance > Immediate test start > Each parameter can be changed during the test
STANDARD PROGRAMS	
Burst Standard test routines F1 IEC 61000-4-4 Level 1 500 U F2 IEC 61000-4-4 Level 2 1000 U F3 IEC 61000-4-4 Level 3 2000 U F4 IEC 61000-4-4 Level 4 4000 U F3 IEC 61000-6-1 Generic 1000 U F6 IEC 61000-6-2 Beneric 2000 U F6 IEC 61000-6-2 Beneric 2000 U F7 Manual test routine 76 F6 F7	THE MOST COMPREHENSIVE STANDARD PROGRAM OF THE INDUSTRY Instead of the Quickstart, you can also load any current standard from the integrated standards and guideline library and easily conduct tests based on the preset parameters. Of course, regular library updates are available from EM TEST.
F1 F2 F3 F4 F5 F6 F7	
USER PROGRAMS	
Burst IEC 61000-4-4 F1 : Synchronized F2 : Random burst release F5 : Uoltage change by T after dt F4 : Frequency sweep in one single burst F5 : Frequency sweep with constant pulse numbers F6 : Frequency sweep with constant burst duration F7 : Change polarity after T F1 F2 F3 F4 F5 F6 F7	CHOOSE FROM PRE-CONFIGURED TEST PARAMETERS You prefer your own test sequences? No problem: The UCS offers comprehensive setting options. Just select what you want.

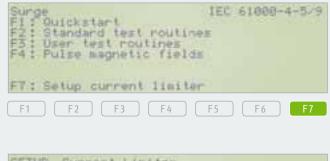
Easy as pie: Thanks to the EM TEST operating concept utilizing function keys and control dials, handling the device is unbelievably simple.



THREE INNOVATIONS. MADE BY EM TEST.

1ST INNOVATION: CURRENT LIMITER em.safe

em.safe – AS SURE AS DEATH AND TAXES





CONFIGURABLE CURRENT LIMITER

Reliable testing with em.safe. An EUT is easily overloaded. And if this EUT is also a prototype, costs will rise in addition to the time delay as well.

em.safe - PROTECTION FOR YOUR EUT

You probably do not pay attention to such details in the course of your everyday work routine but check to see how many devices actually feature such a protective function. You will be surprised.



em.safe

em.safe

2ND INNOVATION: I/U DISPLAY

I/U DISPLAY	
Sunge U = 5000 0 +/- = + tr = 10 s n = 36 pulse:	W = Quickstart cpl = 274 grd cpl = L+N-PE tri = Auto
Uzet = 5888.0 STOP 7#	U = +4710 U Counter I = + 225 A 13

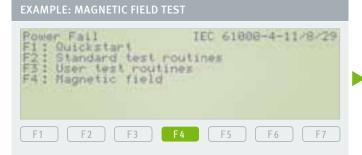
CURRENT AND VOLTAGE DISPLAY

Information about current and voltage levels is important to you as user when performing surge tests. Of course, you also want these values depicted quickly and whenever you need them. The UCS is ready to satisfy your demands.



Of course, all these innovations are found in both, the N5 and the N7 – no doubt.

3RD INNOVATION: MAGNETIC FIELD TESTS



SIMPLY SWITCH ON AND SELECT THE RIGHT MODULE

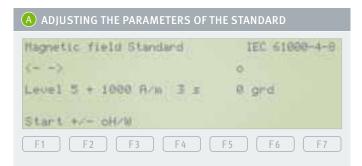
The coil and transformer correction factor must be considered when performing the magnetic field test. The complexity of this process is no longer a problem because the UCS does the calculating for you! Use the F4 function key to access the magnetic field menu directly.

SELECTING THE MAGNETIC FIELD PROGRAM OF STANDARDS

Magnetic fiel	ld	IEC 61000-4-8
F2: Magnetic	field acc. to	IEC 61000-4-8
F7: Setup Ha	gnetic field	

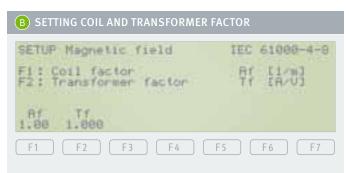
SIMPLIFIED MAGNETIC FIELD TESTING

The parameters of the standard, level 1 to level 5, are already preset and can be selected immediately with the rotary selector.



ADJUSTING THE TEST PARAMETERS

One more step and you already have a choice of the preset program of standards for magnetic fields (F2) or the easy magnetic field setup (F7).



ADJUSTING THE TEST PARAMETERS

You select, the UCS calculates. Formula compilation tables and pocket calculator stay on the shelf. That's what we call "easy"!

OLD MANUAL METHOD:

COIL FACTOR (F_{Coil}) F_{Coil} = H Field [A/m] I Coil [A]

TRANSFORMER FACTOR (FTrafo)

F_{Trafo} = U Prim Transformer [V]

CUSTOMIZED FOR EVERY TEST: THE iec.control



Our software concept is consistently user-friendly. Nothing is simpler — the same applies to the device. Just switch your computer on. And then – here we go!



iec.control – THE TESTWARE.

MANUFACTURER STANDARDS: BE IN THE KNOW WITH ONE OF THE LARGEST LIBRARY OF STANDARDS AND GUIDELINES

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simulation

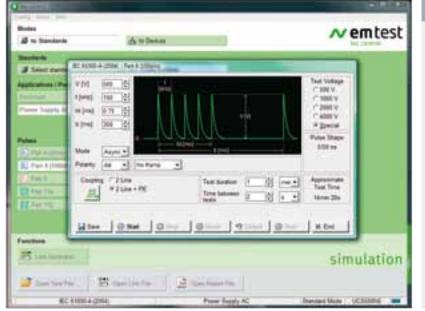
25 Doen Lint File

Dans Peaker Fin

Master all processes with iec.control. At a single glance. Never before was it this easy to generate test sequences. And everything can be configured or modified with the computer.



SPECIFIC TEST SEQUENCES: EASILY GENERATE AND SAVE YOUR OWN TEST SPECIFICATIONS



DETAIL SETTINGS

- > Informal test pulse graphic with parameter description
- > Directly selectable standard level
- > Any parameter setting in SPECIAL mode
- Control buttons effectively placed at always the same position
- > Never loose sight of the test time



LINK FILE GENERATOR

- > Individual TEST files are combined into LINK files
- > LINK files can be repeated as often as desired using the event counter
- > The incurred total test time is calculated and displayed
- > All files can be saved to and loaded from the computer network
- Pause times and test information can be inserted between the individual test routines
- A comment can be entered after each test, which is then inserted automatically into the test report



MEASURING EQUIPMENT: INTEGRATION AND MANAGEMENT OF EXTERNAL MEASURING AND TESTING INSTRUMENTS

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MEASURING INSTRUMENT SELECTION

- Any kind of measuring instruments and oscilloscopes can be integrated using IEEE/GPIB
- > Testing instruments can thus monitor the EUT
- > Oscilloscopes can integrate a plot to monitor the pulse
- Alarm levels can be configured for the optimal measuring sequence control
- > EUT monitoring is realized with the logged measured values and trigger the fail function in an emergency to terminate the test



TEST SEQUENCE

- > Display of all relevant data during the test
- > A clear overview of all finished and still pending tests at all times
- > Measuring instrument information is depicted and alarms are identified
- > All data are prepared in the background for documentation purposes
- > The status bar informs which test simulator is currently active
- Continuous logging of the measured values during testing and also depicted in the test window. The plot with the last pulse of the test is prepared during the pulse monitoring and then inserted into the test report if desired.

From the first standard selection to the finished test report, iec.control provides with everything you could wish for from an easy to use EMC test software.

A brilliant match for the EM TEST hardware.



REPORT GENERATION: EASILY MANAGE, PRINT OUT TESTS AND UPDATE STANDARDS



REPORT GENERATION

- > Layout templates for individual test report designs
- > Complete documentation acc. to DIN EN ISO/IEC 17025
- Clearly structured overview due to graphic with parameter configuration
- If desired, documents are immediately formatted as RTF files
- > The test report is generated automatically during the test and is finished as soon as the test is completed
- Complete test report with plot mapping
- The test report template can be customized and features your own company logo

TEST REPORT

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EXTENDEDCAPABILITIES: ACCESSORIES

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MAGNETIC FIELD COIL



The magnetic field coil can be used for more than just standard tests. When combined with the UCS 500N5/N7, it is possible to simulate any field strengths up to 1,000 A/m. The magnetic field coil (1 m x 1 m) with a 4 cm² cross-section meets the requirements of IEC 61000-4-8 Ed. 2:2009 and IEC/EN 61000-9. A special model with wheels is available as an option.

Type MS 100N: 1,000 A/m, pulsed up to 3,200 A/m

- MC 2630 current transformer for magnetic fields up to 40 A/m acc. to IEC/EN 61000-4-8
- MC 26100 current transformer for magnetic fields up to 1,000 A/m acc. to IEC/EN 61000-4-8

THREE-PHASE COUPLING NETWORKS FOR BURST AND SURGE PULSES ACC. TO IEC 61000-4-4/-5, EN 61000-4-4/-5



The three-phase coupling network CNI 503 is a combination of burst and surge coupling filters and serves to superimpose the interference pulses over the three phase power supplies. Coupling networks of 16 A to 200 A/AC per phase can be provided. Special versions are available, e.g., 690 VAC (L-L) to 100 A and 1,000 VDC / to 63 A for the area of renewable energies (solar technology - inverter technology).

Series CNI 503 to 5 kV: Type: CNI 503Ax, 3 x 480 V / 16 A, 32 A, 63 A*, 100 A*, 200 A* Series CNI 503 to 7 kV: Type: CNI 503Bx, 3 x 480 V / 16 A, 32 A, 63 A*, 100 A*, 200 A* (ANSI / IEC couplings) Series CNI 501/503 to 7 kV: 3 x 690 VAC / max.100 A and 1,000 VDC / max. 63 A * delivered in rack



E and H field sensors help users find weak points as early as the development phase resulting in a considerable cost saving. Application areas range from circuitry to enclosure development.

Type ITP: Broadband sensor set for E fields, type ITP/H: Field sensors for H fields



The standardized capacitive coupling clamp (Type HFK) makes it possible to couple burst pulses onto control and signal lines without galvanic connection.

Type HFK: Acc. to IEC/EN 61000-4-4

TRANSFORMERS AND VARIACS





Auto transformers and motor variacs

Auto transformers are optionally available for voltage dips and interruptions acc. to IEC/EN 61000-4-11.

Various optional motor variacs are available to support voltage variations (IEC/EN 61000-4-11) and magnetic field tests (IEC/EN 61000-4-8).

Type V 4780, Type V 4780S2, Type MV 2616



Our calibration kit to verify the generator at the coaxial output as well as at the coupling network output acc. to IEC/EN61000-4-4, Edition 2. The calibration kit includes the load resistors KW 50 and KW 1000 as well as an adapter to measure the coupling network

Type CA EFT Kit



UCS 500N5 TECHNICAL DATA

ノ い な の 学 様 丽

BURST-MODUL, EFT/N5

Electrical fast transient simulator

CA EFT kit

A6dB

ITP/H

ITP

BURST MODULE, EFT/N5	
Test voltage	200 V - 5,500 V ± 10%,
	100 V-2,750 V ± 10% (50 T)
Pulse shape	5/50 ns at 50 T and 1,000 T
Rise time (tr)	5 ns ± 30% at 50 T,
	5 ns ± 30% at 1,000 T
Pulse duration	50 ns ± 30% at 50 T,
	50 ns –15/+100 ns at 1,000 T
Source impedance	50 T
Polarity	Positive/negative
TRIGGER (BURST)	
Dulco triggor	Automatic manual automal
Pulse trigger	Automatic, manual, external
Synchronization	0° – 360°, resolution 1°
Durant durantians (tal)	(16 – 500 Hz)
Burst duration (td)	td = 0.10 ms - 999 ms
Repetition rate (tr)	tr = 10 ms - 9,999 ms
Burst frequency	f = 0.1 kHz - 1,000 kHz
Test duration	T = 0:01 min. – 99:59 min.
	T > 99:59 min> infinite
OUTPUTS	
Direct	Via 50 T coaxial
Coupling modes	L, N, PE; all combinations
DUT supply	AC: 300 V/16 A; 50/60 Hz
	DC: 300 V/16 A
CRO trigger	5 V trigger signal for oscilloscope
TEST ROUTINES	
Quickstart	Parameter adjustable online,
	easy handling
Standard test routines	Acc. to IEC/EN 61000-4-4
	Acc. to IEC/EN 61000-6-1/-2
	Manual standard test routine
User-defined test routines	Synchronous burst triggering
User-defined test fournes	Random burst release
	Changing voltage after T
	Frequency sweep (single burst)
	Frequency sweep (single burst) Frequency sweep (constant pulse number)
	Frequency sweep (constant burst duration)
	Changing polarity after T
ACCESSORIES (BURST)	
HFK	Capacitive coupling clamp
	Acc. to IEC/EN 61000-4-4
KW 50	100:1 load resistor, 50 T
KW 1000	500:1 load resistor, 1,000 T
CA FFT L'	

Calibration kit for pulse verification Consists of KW 50, KW 1000 and adapters

Field sensor kit to generate electrical fields

Field sensor kit to generate magnetic fields

6 dB attenuator, 50 T

SURGE-MODUL, VCS/N5

Combination wave simulator

MODUL SURGE, VCS/N5	M N
Voltage (o.c.)	160 V - 5,000 V ± 10%
Rise time	1.2 μs ± 30%
Decay time to half value	50 μs ± 20%
Current (s.c.)	Max. 2,500 A ± 10%
Rise time	8 μs ± 20%
Decay time to half value	20 μs ± 20%
Polarity	Positive/negative/alternating
Counter	1 – 30,000 or endless, adjustable
TRIGGER	
Pulse trigger	Automatic, manual, external
Synchronization	0° – 360°, resolution 1°
Repetition rate	Max. 1 Hz (1 s – 999 s)
OUTPUTS	
Direct	Via HV connectors, Zi = 2 T
Couplings	Line to line
	Line to ground (PE)
DUT supply	AC: 300 V/16 A; 50/60 Hz
	DC: 300 V/16 A
CRO trigger	5 V trigger signal for oscilloscope
MEASURING EQUIPMENT	
CRO Û monitor	10 Vp/5,000 V
CRO Î monitor	10 Vp/2,500 A
Peak voltage	5,000 V in LC display
Peak current	2,500 A in LC display
TEST PROCEDURES	
Quickstart	Parameter adjustable online,
	easy handling
Standard test routines	Acc. to IEC/EN 61000-4-5
	Acc. to IEC/EN 61000-6-1/-2
	Manual standard test routines
User-specific test routines	Changing coupling after n pulses
	Changing voltage after T
	Changing phase angle after n pulses
Pulsed magnetic field	Acc. to IEC/EN 61000-4-9
•	Test level 100, 300 and 1,000 A/m, test level
	variable adjustable using Quickstart
ACCESSORIES (COUPLING N	IETWORKS)

CNV504N	Coupling network for 4 signal/data lines
	acc. to IEC/EN 61000-4-5
CNV508N	Coupling network for 8 signal/data lines
	acc. to IEC/EN 61000-4-5

POWER FAIL MODULE PFS/N5

Power fail simulator

POWER FAIL MODULE, PFS	5/N5 V
Channel PF1/PF2	AC voltage: max. 300 V
	AC current: max. 16 A
	DC voltage: max. 300 V
	DC current: max 16 A (IEC/EN 61000-4-29)
Frequency	16 Hz – 500 Hz
Switching time	< 5 us at 100 T resistive load
Inrush current	> 500 A
Protection	Both channels short-circuit protected
TRIGGER	
Trigger	Automatic, manual, external
Synchronization	0° – 360°, resolution 1°
	(16 – 500 Hz)
Repetition rate	10 ms – 9,999 s
Test time	20 μs – 9,999 s
OUTPUTS	
DUT terminals	L, N and PE
CRO trigger	5 V trigger signal for oscilloscope
	-
MEASURING EQUIPMENT	
DUT voltage	In display
DUT current	In display
MON V	Measuring DUT voltage with integrated
	divider 100:1
MON I	Measuring DUT current
	10 mV/A; max. 1,000 A
TEST ROUTINES	
Quickstart	Parameter adjustable online, easy handling
Standard test routines	Acc. to IEC/EN 61000-4-11 for AC supply
	Acc. to IEC/EN 61000-4-29 for DC supply
	Acc. to IEC/EN 61000-6-1, -6-2 man. test routines
User-specific test routines	Voltage variations
	Controlling external variacs
	Changing phase angle after n events
	Changing event duration after n events
	Inverse mode
50/60 Hz magnetic field	Acc. to IEC/EN 61000-4-8
	Test level 1, 3, 10 and 30 A/m
	with external current transformer MC2630
	Test level 100, 300 and 1,000 A/m with current
	transformer MC26100
ACCESSORIES	
V4780	Auto transformer with taps
	acc. to IEC/EN 61000-4-11 Ed. 2

V4780	Auto transformer with taps
	acc. to IEC/EN 61000-4-11 Ed. 2
V4780 S2	Auto transformer with automatically
	switched taps acc. to IEC/EN 61000-4-11 Ed.2
MV2616	Motor variac (0 – 260 V, 16 A)
MS100N	Magnetic field coil, 1 m x 1 m
MC2630	Current transformer for magnetic fields up to
	30 A/m
MC26100	Current transformer for magnetic fields up to
	1,000 A/m
CA PFS	Calibration box to verify the inrush current
	acc. to IEC/EN 61000-4-11

TELECOM SURGE MODULE*

Telecom surge simulator – TSurge5

TSURGE5 MODULE	
Test voltage	160 V-5,000 V ± 10%
Storage capacitor	20 uF
Polarity	Positive, negative, alternating
Counter	1 – 30,000 or infinite, adjustable
	acc. to ITU and ETSI recommendations
Rise time	10 µs ± 30%
Pulse duration	700 µs ± 20%
	Acc. to FCC part 68, pulse B
Rise time	9 μs ± 30%
Pulse duration	720 µs ± 20%
Output current	6 A-125 A (short-circuit)
Rise time	5 μs ± 30%
Pulse duration	320 μs ± 20%
	Acc. to IEC/EN 61000-4-5
Rise time	6,5 μs ± 30%
Pulse duration	700 µs ± 20%
Output current	6 A – 125 A (short-circuit)
Rise time	4 μs ± 20%
Pulse duration	300 μs ± 20%
TRIGGER	
Trigger	Automatic, manual, external
Repetition rate	Max. 0.5 Hz (2 s – 999 s)
OUTPUTS (TELECOM SURGE	:)
Acc. to ITU	For 2-conductor T1/T2, 25 T each
Acc. to FCC part 68	For 2-conductor T1/T2, 25 T each
Acc. to IEC/EN 61000-4-5	For 4-conductor T1, T2, T3 and T4, 100 T each
OPTIONS	
CNV 504S1	Coupling filter for 4 telecommunication lines (IEC/EN 61000-4-5)
CNV 508S1	Coupling filter for 8 telecommunication lines (IEC/EN 61000-4-5)
*Optionally available	

*Optionally available

GENERAL DATA

CONNECTIONS/PORTS	
Serial interface	USB
Parallel interface	IEEE 488, addresses 1 – 30
Analog output	0 – 10 VDC to control external transformers
CN interface	15-pin SubD connector to control
	external couplers
Fault inputs	DUT monitoring via
	Fail 1 and Fail 2 input (each 1)
DIMENSIONS AND WEIGHTS	5
Dimensions	19"/3 HU,
	19"/6 HU (with TSurge5 module)
Weight	Approx. 25 kg
MAINS	
Line voltage	115/230 V AC (+10%/-15%)
Power	Approx. 75 W
Frequency	50/60 Hz
Fuses	2xT2A (230 V)/2xT4A (115 V)
SAFETY	
Safety standard	IEC/EN 61010
Safety circuit	Control input (24 VDC)
Warning lamps	Potential-free (230 V / 6 A)
SCOPE OF DELIVERY	
Power cable	Acc. to destination country
Cable to DUT supply	Acc. to destination country
DUT adapter	Acc. to destination country
User manual	
Calibration certificate	
USB cable (USB A/B 3 m)	
Control software iec.control	
ACCESSORIES	
CNI 503Ax	3-phase coupling network
	Acc. to IEC/EN 61000-4-4 and 4-5
	Up to 200 A per phase
CNI 508N1	Coupling network for fast communication lines
	acc. to IEC/EN 61000-4-5.
iec.control 1	Control and documentation software
	Incl. standard test routines and report options
	Integration of any measuring equipment and
	oscilloscopes using IEEE-GPIB commands.

Information about delivery scope, design, performances, capacities, dimensions, and weights correspond with the data available at the time of printing. Subject $% \left({{{\left[{{{\rm{A}}} \right]}_{{\rm{A}}}}_{{\rm{A}}}} \right)$ to change. © EM TEST 2010

UCS 500N7 TECHNICAL DATA

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BURST MODULE, EFT/N7

Electrical fast transient simulator

ITP/H

BURST MODULE, EFT/N7	
Test voltage	200 V - 5,500 V ± 10%;
	100 V – 2,750 V ± 10% (50 T)
Pulse shape	5/50 ns at 50 T and 1,000 T
Rise time (tr)	5 ns ± 30% at 50 T,
	5 ns ± 30% at 1,000 T
Burst range (td)	50 ns ± 30% at 50 T,
	50 ns –15/+100 ns at 1,000 T
Source impedance	50 T
Polarity	Positive/negative
TRIGGER	
Burst triggering	Automatic, manual, external
Synchronization	0° – 360°, resolution 1°
	(16 – 500 Hz)
Burst duration	td = 0.10 ms – 999 ms
Repetition rate	tr = 10 ms – 9,999 ms
Burst frequency	f = 0.1 kHz - 1,000 kHz
Test duration	T = 0:01 min - 99:59 min
	T > 99:59 min> infinite
OUTPUTS	
Direct	Via 50 T coaxial
Coupling modes	L, N, PE; all combinations
DUT supply	AC: 300 V / 16 A; 50/60 Hz
	DC: 300 V / 16 A
CRO-Trigger	5 V trigger signal for oscilloscope
TEST ROUTINES	
Quickstart	Parameter adjustable online,
	easy handling
Standard test routines	Acc. to IEC/EN 61000-4-4,
	Acc. to IEC/EN 61000-6-1/-2
	Manual standard test routines
User-defined test routines	Synchronous burst triggering
	Random burst release
	Changing voltage after T
	Frequency sweep (single burst)
	Frequency sweep (constant pulse number) Frequency sweep (constant burst duration)
	Changing polarity after T
ACCESSORIES	
HFK	Capacitive coupling clamp
1411 50	Acc. to IEC/EN 61000-4-4
KW 50	100:1 load resistor, 50 T
KW 1000	500:1 load resistor, 1,000 T
CA EFT Kit	Calibration kit for pulse verification consisting of KW 50, KW 1000 and adapters
AcdP	
A6dB ITP	6 dB attenuator, 50 T Field sensor kit to generate electrical fields
	Field sensor kit to generate electrical fields

Field sensor kit to generate magnetic fields

SURGE MODULE, VCS/N7

Combination wave simulator

SURGE MODULE, VCS/N7			
Voltage (open)	250 V - 7,000 V ± 10%		
Rise time	1.2 us ± 30%		
Decay time to half value	50 µs ± 20%		
Current (short-circuit)	Max. 3,500 A ± 10%		
Rise time	8 μs ± 20%		
Decay time to half value	20 µs ± 30%		
Polarity	Positive, negative, alternating		
Counter	1 – 30,000 or endless, adjustable		
OUTPUTS			
Direct	Via HV connectors, Zi = 2 T		
Couplings	Acc. to IEC/EN 61000-4-5		
	Line to line with 2 T		
	Line to ground with 12 T		
	Acc. to ANSI/IEEE C62.41		
	Line to line with 2 T		
	Line(s) to ground with 2 T		
DUT supply	AC: 300 V / 16 A; 50/60 Hz		
	DC: 300 V / 16 A		
CRO trigger	5 V trigger signal for oscilloscope		
MEASURING EQUIPMENT			
CRO Û monitor	10 Vp at 7,000 V		
CRO Î monitor	10 Vp at 3,500 A		
Peak voltage	7,000 V in LC display		
Peak current	3,500 A in LC display		
TEST ROUTINES			
Quickstart	Parameter adjustable online,		
	easy handling		
Standard test routines	Acc. to IEC/EN 61000-4-5		
	Acc. to IEC/EN 61000-6-1/-2		
	Manual standard test routines		
User-specific test routines	Changing polarity after n pulses		
	Changing coupling after n pulses		
	Changing voltage after T		
	Changing phase angle after n pulses		
Magnetic field,	Acc. to IEC/EN 61000-4-9		
pulsed	Test level 100, 200 and 1,000 A/m, test level		
	variable adjustable using Quickstart		
ACCESSORIES (COUPLING N	IFTWORKS)		

ACCESSORIES (COUPLING NETWORKS)

CNV504N	Coupling network for 4 signal/ data lines acc. to IEC/EN 61000-4-5
CNV508N	Coupling network for 8 signal/ data lines acc. to IEC/EN 61000-4-5

POWER FAIL MODULE PFS/N7

Power fail simulator

POWER FAIL MODULE, P	FS/N7 🛛 🚺 🔽
Channel PF1/PF2	AC voltage: max. 300 V
	AC current: max. 16 A
	DC voltage: max. 300 V
	DC current: max 16 A (IEC/EN 61000-4-29)
Frequency	16 Hz – 500 Hz
Switching time Inrush current	< 5 us at 100 T resistive load
Protection	> 500 A Both channels short-circuit protected
Trotection	Both channels short-circuit protected
TRIGGER	
Trigger	Automatic, manual, external
Synchronization	0° – 360°, resolution 1°
	(16 – 500 Hz)
Repetition rate	10 ms – 9,999 s
Test time	20 µs – 9,999 s
OUTPUTS	
DUT connection	L, N and PE
CRO trigger	5 V trigger signal for oscilloscope
MEASURING EQUIPMEN	
DUT voltage	In display
DUT current	In display
MONV	Measuring DUT voltage with
	integrated divider 100:1
MONI	Measuring DUT current;
	10 mV/A; max. 1,000 A
TEST ROUTINES	
Quickstart	Parameter adjustable online,
	easy handling
Standard test routines	Acc. to IEC/EN 61000-4-11 for AC supply
	Acc. to IEC/EN 61000-4-29 for DC supply
	Acc. to IEC/EN 61000-6-1, 6-2 man. test routines
User-specific test routines	Voltage variation, external variac control
	Changing phase angle after n events,
	Changing event duration after n events, Inverse mode
50/60 Hz magnetic field	Acc. to IEC/EN 61000-4-8
50/60 Hz magnetic field	Test level 1, 3, 10 and 30 A/m
	with external current transformer MC2630
	Test level 100, 300 and 1,000 A/m
	with external current transformer MC26100
ACCESSORIES	
1// 700	
V4780	Auto transformer with taps
V4780 S2	acc. to IEC 61000-4-11 Ed. 2
V470032	Auto transformer with automatically switched taps acc. to IEC 61000-4-11 Ed.2
	Switched taps acc. to IEC 01000-4-11 Ed.2

Motor variac (0 – 260 V, 16 A)

Magnetic field coil 1 m x 1 m $\,$

acc. to IEC/EN 61000-4-11

up to 30 A/m

up to 1,000 A/m

Current transformer for magnetic fields

Current transformer for magnetic fields

Calibration box to verify the inrush current

RINGWAVE MODULE* RWG/N7

Oscillatory wave simulator

RINGWAVE MODULE, RWG/I	N7	√." 🔨	
Test voltage	250 V - 6,000 V ± 10%		
Voltage	Pulse shape (open circuit)		
Rise time	(1st peak) 0.5 μs ± 30%		
Oscillation frequency	100 kHz ± 20%		
Decay values	Peak 2 to Peak 1 = 40 - 110%		
	Peak 3 to Peak 2 = 40 - 80%		
	Peak 4 to Peak 3 = 40 - 80%		
Current	Pulse shape (short-circuit)		
Rise time	<= 1.0 μs		
Oscillation frequency	100 kHz ± 20%		
Source impedance	12 T and 30 T		
Peak current	Acc. to selected source impedance		
Polarity	Positive/negative		
TRIGGER			
Pulse triggering	Automatic, manual, external		
Synchronization	0° – 360°, resolution 1°		
Repetition rate	Max. 1 Hz (1 s – 999 s)		
OUTPUTS			
Direct	Via HV connector		
Coupling types	L, N, PE; line to line		
	and line to ground		
DUT supply	AC: 300 V/16 A, 50/60 Hz		
	DC: 300 V/16 A		
CRO trigger	5 V trigger signal for oscilloscope		
TEST ROUTINES			
Quickstart	Parameter adjustable online, easy handling		
Standard test routines	Acc. to ANSI/IEEE C62.41		
	Acc. to IEC/EN 61000-4-12		
Ontionally available			

*Optionally available

MV2616

MS100N

MC2630

MC26100

CA PFS

TELECOM SURGE MODULE*

Telecom surge simulator – TSurge7

TSURGE MODULE, TSURGE7

TSURGE MODULE, TSURGE	7 🔽 🔽
Test voltage (open)	250 V - 7,000 V ± 10%
Storage capacitor	20 uF
Polarity	Positive, negative, alternating
Counter	1 – 30,000 or infinite, adjustable acc. to ITU and ETSI recommendations
Rise time	10 µs ± 30%
Pulse duration	700 μs ± 20% Acc. to FCC part 68, pulse B
Rise time	9 μs ± 30%
Pulse duration	720 µs ± 20%
Output current	6 A – 175 A (short-circuit)
Rise time	5 μs ± 30%
Pulse duration	320 μs ± 20% Acc. to IEC/EN 61000-4-5
Rise time	6.5 μs ± 30%
Pulse duration	700 μs ± 20%
Output current	6 A – 175 A (short-circuit)
Rise time	4 μs ± 20%
Pulse duration	300 μs ± 20%
TRIGGER	
Trigger	Automatic, manual, external
Repetition rate	Max. 0.33 Hz (3 s – 999 s)
OUTPUTS	
Acc. to ITU	2-conductor T1/T2, 25 T each
Acc. to FCC part 68	2-conductor T1/T2, 25 T each

to FCC part 6 lor 11/12, 25 Teacri Acc. to IEC 61000-4-5 4-conductor T1/T2, 100 T each

CNV 504S1	Coupling filter for 4 telecommunication lines
	(IEC/EN 61000-4-5)
CNV 508S1	Coupling filter for 8 telecommunication lines
	(IEC/EN 61000-4-5)

*Optionally available

GENERAL DATA

CONNECTIONS/PORTS	
Serial interface	USB
Parallel interface	IEEE 488, addresses 1 – 30
Analog output	0 – 10 VDC to control
	external transformers
CN interface	15-pin SubD connector to control external coupling networks
Fail inputs	DUT monitoring via Fail1 and Fail2 inputs
DIMENSIONS AND WEIGHTS	5
Housing	19", 6 HU, L = 532 mm
Weight	Approx. 29 kg
MAINS	
Supply voltage	115/230 VAC +10%/-15%
Power	Approx. 75 W
Frequency	50/60 Hz
Fuses	2 x T2A (230 V) or 2 x T4A (115 V)
SAFETY	
Safety standard	IEC/EN 61010
Safety circuit	Control input (24 VDC)
Warning lamps	Potential-free (230 V/6 A)
SCOPE OF DELIVERY	
Power cable	Acc. to destination country
Cable to DUT supply	Acc. to destination country
DUT adapter	Acc. to destination country
User manual	
Calibration certificate	
USB cable (USB A/B 3 m)	
Control software iec.control	
ACCESSORIES	
CNI 503Bx	3-phase coupling/decoupling networks Acc. to IEC/EN 61000-4-4/-5 as well as ANSI/IEEE C62.41 up to 200 A per phase
CNI 508N1	Coupling network for fast communication lines
	acc to IEC/EN (1000 / E

acc. to IEC/EN 61000-4-5. Control and documentation software Incl. standard test routines and report options Integration of any measuring equipment and oscilloscopes using IEEE-GPIB commands.

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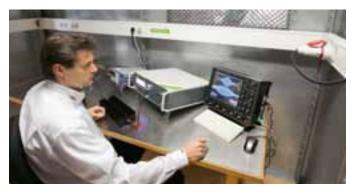
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